

試験報告書番号: Test report no.:	JP21ZNO0-001	申請受理番号: Order no.:	P00341793 (150245498)	頁 1 / 17 Page 1 / 17
申請者参照番号: Client reference no.:	2047560	申請日: Order date:	2021-07-28	
申請者: Client:	FUJITSU LIMITED 1-5-2, Higashi-Shinbashi, Minato-ku, Tokyo, 105-7123, Japan			
試験品: Test item:	Fujitsu Intelligent Society Solution Distributed Energy Management solution OpenADR VTN module 2.0b			
識別表示 / 型名: Identification / Type no.:	N/A / 1.0			
申請内容: Order content:	OpenADR Certification Test			
適用した試験基準: Test specification:	OpenADR 2.0b Certification Test Specification Version 1.1.5 OpenADR 2.0a Certification Test Specification Version 1.1.3			
サンプル受理日: Date of sample receipt:	N/A			
製造番号: Test sample no.:	N/A			
試験期間: Testing period:	2021-09-27 ~ 2021-09-29			
試験場所: Place of testing:	TÜV Rheinland Japan Ltd. 3-19-5 Shin-Yokohama, Kohoku-ku Yokohama 222-0033, Japan			
試験所: Testing laboratory:	TÜV Rheinland Japan Ltd.			
試験結果: Test result*:	適合 / Pass			
試験者: tested by:		照査者: authorized by:		
日付: 2021-09-29 Date:	Takeshi Senuma	発行日: 2021-09-29 Issue Date:	Norikazu Mizuki	
職位 / Position:	専門家 / Expert	職位 / Position:	専門家 / Expert	
備考 / Other:				
納品時の試験品の状態: Condition of the test item at delivery:		試験品は完全で破損はない Test item complete and undamaged		
*凡例:	1 = 優 P(ass) = 適合	2 = 良	3 = 可 F(ail) = 不適合	4 = 準可 N/A = 適用外
* Legend:	1 = very good P(ass) = passed a.m. test specification(s)	2 = good	3 = satisfactory F(ail) = failed a.m. test specification(s)	5 = 不可 N/T = 試験せず
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1 General Product Information

1.1 Client Information

Company Name: see page 1
Address: see page 1
Contact Person: Etsuko Katou
Phone: + 81-3-6252-2220
E-mail: eh-kato@fujitsu.com

1.2 General SUT Information

The system under test is software implementation of OpenADR protocol installed on Cloud.

Serial Number: N/A
Hardware Version: N/A
Firmware version: 1.0

1.3 General EUT Description

Equipment under test: see page 1

1.4 Profile

Product type: VTN
OpenADR profile: 2.0b, 2.0a
Mode: Pull, Push
Transport: Simple HTTP, XMPP
Security: Standard Security

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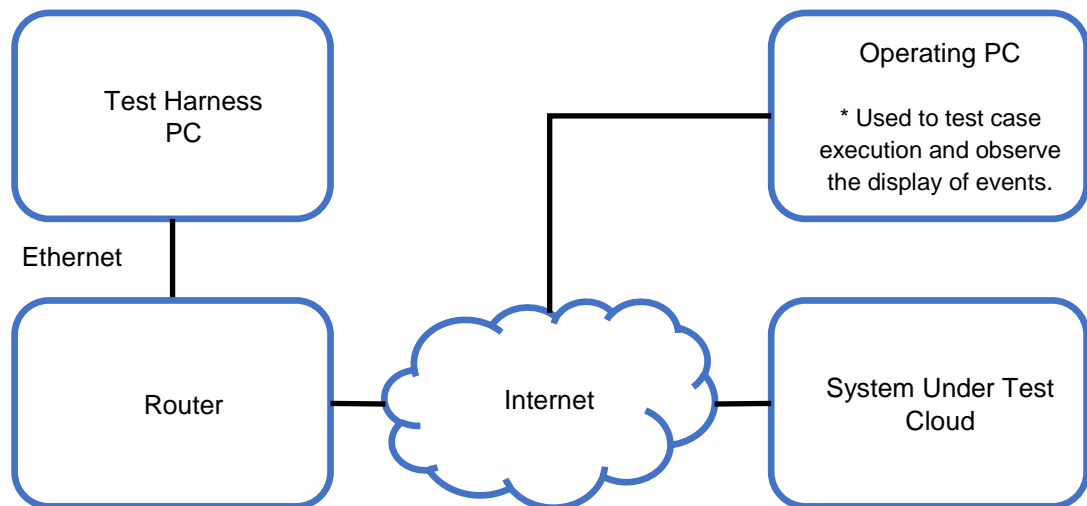
2 Testing Laboratory

see page 1

2.1 Test Equipment

Equipment ID	Model Product name	Manufacture	Category	Version
1800528	OpenADR Test Harness for 2.0b	QualityLogic	Software	1.1.5
1800440	OpenADR Test Harness for 2.0a	QualityLogic	Software	1.1.3

2.2 Test Setup



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3 Information about Test Results

3.1 General

Documentation of tested devices and results:

The complete set of measurement results is stored at the TÜV Rheinland Japan Ltd. test laboratory and is available on demand.

Interpretation of test results:

The results of the inspection are described on the following pages. "Pass" in the test result list of this test report means the performed test according to the test specification was verified and that the tested device is conformant to the specification. "Fail" means that the performed test according to the test specification was verified and the tested device is not conformant to the specification or that test didn't run to completion because the tested device is not conformant to the specification. "N/A" means the test cases are optional and/or not applicable to the tested device.

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4 Test Results

4.1 Profile 2.0b

4.1.1 VTN Pull Tests

4.1.1.1 EiRegisterParty Service

No.	Test Case Name	Date	Result
01	N1_0010_TH_VEN	Sep 27 2021	PASS
02	N1_0015_TH_VEN	Sep 27 2021	PASS
03	N1_0020_TH_VEN	Sep 27 2021	PASS
04	N1_0025_TH_VEN	Sep 27 2021	PASS
05	N1_0030_TH_VEN	Sep 27 2021	PASS
06	N1_0040_TH_VEN	Sep 27 2021	PASS
07	N1_0050_TH_VEN	Sep 27 2021	PASS
08	N1_0060_TH_VEN	Sep 27 2021	PASS
09	N1_0065_TH_VEN	Sep 27 2021	PASS
10	N1_0070_TH_VEN	Sep 27 2021	PASS
11	N1_0080_TH_VEN	Sep 27 2021	PASS

4.1.1.2 EiOpt Service

No.	Test Case Name	Date	Result
01	P1_2010_TH_VEN	Sep 27 2021	PASS
02	P1_2015_TH_VEN	Sep 27 2021	PASS
03	P1_2020_TH_VEN	Sep 27 2021	PASS
04	P1_2030_TH_VEN	Sep 27 2021	PASS
05	P1_2040_TH_VEN	Sep 27 2021	PASS
06	P1_2050_TH_VEN	Sep 27 2021	PASS

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4.1.1.3 EiReport Service

No.	Test Case Name	Date	Result
01	R1_3010_TH_VEN	Sep 27 2021	PASS
02	R1_3020_TH_VEN	Sep 27 2021	PASS
03	R1_3025_TH_VEN	Sep 27 2021	PASS
04	R1_3027_TH_VEN	Sep 27 2021	PASS
05	R1_3030_TH_VEN	Sep 27 2021	PASS
06	R1_3040_TH_VEN	Sep 27 2021	PASS
07	R1_3045_TH_VEN	Sep 27 2021	PASS
08	R1_3050_TH_VEN	N/A	N/A
09	R1_3060_TH_VEN	N/A	N/A
10	R1_3070_TH_VEN	Sep 27 2021	PASS
11	R1_3080_TH_VEN	N/A	N/A
12	R1_3090_TH_VEN	N/A	N/A
13	R1_3100_TH_VEN	N/A	N/A
14	R1_3120_TH_VEN	N/A	N/A
15	R1_3130_TH_VEN	Sep 27 2021	PASS
16	R1_3150_TH_VEN	Sep 27 2021	PASS
17	R1_3160_TH_VEN	Sep 27 2021	PASS
18	R1_3170_TH_VEN	N/A	N/A
19	R1_3180_TH_VEN	Sep 27 2021	PASS
20	R1_3190_TH_VEN	Sep 27 2021	PASS

4.1.1.4 EiEvent Service

No.	Test Case Name	Date	Result
01	E1_1010_TH_VEN	Sep 27 2021	PASS
02	E1_1020_TH_VEN	Sep 27 2021	PASS
03	E1_1025_TH_VEN	Sep 27 2021	PASS
04	E1_1027_TH_VEN	Sep 27 2021	PASS
05	E1_1030_TH_VEN	Sep 27 2021	PASS
06	E1_1040_TH_VEN	Sep 27 2021	PASS
07	E1_1050_TH_VEN	Sep 27 2021	PASS
08	E1_1055_TH_VEN	Sep 27 2021	PASS
09	E1_1060_TH_VEN	Sep 27 2021	PASS
10	E1_1065_TH_VEN	Sep 27 2021	PASS
11	E1_1070_TH_VEN	N/A	N/A
12	E1_1080_TH_VEN	Sep 27 2021	PASS
13	E1_1090_TH_VEN	N/A	N/A

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4.1.1.5 EiEvent Ported A Profile

No.	Test Case Name	Date	Result
01	A_E3_0420_TH_VEN	Sep 27 2021	PASS
02	A_E3_0430_TH_VEN	Sep 27 2021	PASS
03	A_E3_0432_TH_VEN	Sep 27 2021	PASS
04	A_E3_0435_TH_VEN	Sep 27 2021	PASS
05	A_E3_0440_TH_VEN	Sep 27 2021	PASS
06	A_E3_0450_TH_VEN	Sep 27 2021	PASS
07	A_E3_0452_TH_VEN	Sep 27 2021	PASS
08	A_E3_0454_TH_VEN	Sep 27 2021	PASS
09	A_E3_0468_TH_VEN	Sep 27 2021	PASS
10	A_E3_0470_TH_VEN	Sep 27 2021	PASS
11	A_E3_0474_TH_VEN	Sep 27 2021	PASS
12	A_E3_0480_TH_VEN	Sep 27 2021	PASS
13	A_E3_0484_TH_VEN	Sep 27 2021	PASS
14	A_E3_0490_TH_VEN	Sep 27 2021	PASS
15	A_E3_0492_TH_VEN	Sep 27 2021	PASS
16	A_E3_0494_TH_VEN	Sep 27 2021	PASS
17	A_E3_0496_TH_VEN	Sep 27 2021	PASS
18	A_E3_0498_TH_VEN	Sep 27 2021	PASS
19	A_E3_0500_TH_VEN	Sep 27 2021	PASS
20	A_E3_0510_TH_VEN	Sep 27 2021	PASS
21	A_E3_0525_TH_VEN	Sep 27 2021	PASS
22	A_E3_0527_TH_VEN	Sep 27 2021	PASS
23	A_E3_0655_TH_VEN	Sep 27 2021	PASS
24	A_E3_0657_TH_VEN	Sep 27 2021	PASS
25	A_E3_0680_TH_VEN	Sep 27 2021	PASS
26	A_E3_0685_TH_VEN	Sep 27 2021	PASS
27	A_E3_0710_TH_VEN	Sep 27 2021	PASS
28	A_E3_0720_TH_VEN	Sep 27 2021	PASS
29	A_E3_0730_TH_VEN	Sep 27 2021	PASS
30	A_E3_0750_TH_VEN	Sep 27 2021	PASS
31	A_E3_0780_TH_VEN	Sep 27 2021	PASS

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4.1.1.6 General Tests

No.	Test Case Name	Date	Result
01	G1_4005_TH_VEN	Sep 27 2021	PASS
02	G1_4007_TH_VEN	Sep 27 2021	PASS
03	G1_4010_TH_VEN	Sep 27 2021	PASS
04	G1_4011_TH_VEN	Sep 27 2021	PASS
05	G1_4012_TH_VEN	Sep 27 2021	PASS
06	G1_4015_TH_VEN	N/A	N/A
07	G1_4020_TH_VEN_1	Sep 27 2021	PASS
08	G1_4030_TH_VEN	Sep 27 2021	PASS

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4.1.2 VTN Push Tests

4.1.2.1 EiRegisterParty Service

No.	Test Case Name	Date	Result
01	N0_5010_TH_VEN	Sep 27 2021	PASS
02	N0_5015_TH_VEN	Sep 27 2021	PASS
03	N0_5020_TH_VEN	Sep 27 2021	PASS
04	N0_5025_TH_VEN	Sep 27 2021	PASS
05	N0_5030_TH_VEN	Sep 27 2021	PASS
06	N0_5040_TH_VEN_1	Sep 27 2021	PASS
07	N0_5050_TH_VEN_1	Sep 27 2021	PASS
08	N0_5060_TH_VEN	Sep 27 2021	PASS
09	N0_5065_TH_VEN	Sep 27 2021	PASS
10	N0_5070_TH_VEN	Sep 27 2021	PASS
11	N0_5080_TH_VEN	Sep 27 2021	PASS

4.1.2.2 EiOpt Service

No.	Test Case Name	Date	Result
01	P0_7010_TH_VEN	Sep 27 2021	PASS
02	P0_7015_TH_VEN	Sep 27 2021	PASS
03	P0_7020_TH_VEN	Sep 27 2021	PASS
04	P0_7030_TH_VEN	Sep 27 2021	PASS
05	P0_7040_TH_VEN	Sep 27 2021	PASS
06	P0_7050_TH_VEN	Sep 27 2021	PASS

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4.1.2.3 EiReport Service

No.	Test Case Name	Date	Result
01	R0_8010_TH_VEN_1	Sep 27 2021	PASS
02	R0_8020_TH_VEN_1	Sep 27 2021	PASS
03	R0_8025_TH_VEN_1	Sep 27 2021	PASS
04	R0_8027_TH_VEN_1	Sep 27 2021	PASS
05	R0_8030_TH_VEN_1	Sep 27 2021	PASS
06	R0_8040_TH_VEN_1	Sep 27 2021	PASS
07	R0_8045_TH_VEN_1	Sep 27 2021	PASS
08	R0_8050_TH_VEN_1	N/A	N/A
09	R0_8060_TH_VEN_1	N/A	N/A
10	R0_8070_TH_VEN	Sep 27 2021	PASS
11	R0_8080_TH_VEN_1	N/A	N/A
12	R0_8090_TH_VEN_1	N/A	N/A
13	R0_8100_TH_VEN_1	N/A	N/A
14	R0_8120_TH_VEN_1	N/A	N/A
15	R0_8130_TH_VEN_1	Sep 27 2021	PASS
16	R0_8150_TH_VEN_1	Sep 27 2021	PASS
17	R0_8160_TH_VEN_1	Sep 27 2021	PASS
18	R0_8170_TH_VEN_1	N/A	N/A
19	R0_8180_TH_VEN_1	Sep 27 2021	PASS
20	R0_8190_TH_VEN_1	Sep 27 2021	PASS

4.1.2.4 EiEvent Service

No.	Test Case Name	Date	Result
01	E0_6010_TH_VEN_1	Sep 28 2021	PASS
02	E0_6020_TH_VEN_1	Sep 28 2021	PASS
03	E0_6025_TH_VEN_1	Sep 28 2021	PASS
04	E0_6027_TH_VEN_1	Sep 28 2021	PASS
05	E0_6030_TH_VEN_1	Sep 28 2021	PASS
06	E0_6040_TH_VEN_1	Sep 28 2021	PASS
07	E0_6050_TH_VEN	Sep 28 2021	PASS
08	E0_6055_TH_VEN_1	Sep 28 2021	PASS
09	E0_6060_TH_VEN_1	Sep 28 2021	PASS
10	E0_6065_TH_VEN_1	Sep 28 2021	PASS
11	E0_6070_TH_VEN_1	N/A	N/A
12	E0_6080_TH_VEN_1	Sep 28 2021	PASS
13	E0_6090_TH_VEN_1	N/A	N/A

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4.1.2.5 EiEvent Ported A Profile

No.	Test Case Name	Date	Result
01	A_E2_0430_TH_VEN_1	Sep 28 2021	PASS
02	A_E2_0432_TH_VEN_1	Sep 28 2021	PASS
03	A_E2_0435_TH_VEN_1	Sep 28 2021	PASS
04	A_E2_0440_TH_VEN_1	Sep 28 2021	PASS
05	A_E2_0450_TH_VEN_1	Sep 28 2021	PASS
06	A_E2_0452_TH_VEN_1	Sep 28 2021	PASS
07	A_E2_0454_TH_VEN_1	Sep 28 2021	PASS
08	A_E2_0468_TH_VEN_1	Sep 28 2021	PASS
09	A_E2_0470_TH_VEN_1	Sep 28 2021	PASS
10	A_E2_0474_TH_VEN_1	Sep 28 2021	PASS
11	A_E2_0480_TH_VEN_1	Sep 28 2021	PASS
12	A_E2_0484_TH_VEN_1	Sep 28 2021	PASS
13	A_E2_0490_TH_VEN_1	Sep 28 2021	PASS
14	A_E2_0492_TH_VEN_1	Sep 28 2021	PASS
15	A_E2_0494_TH_VEN_1	Sep 28 2021	PASS
16	A_E2_0496_TH_VEN_1	Sep 28 2021	PASS
17	A_E2_0498_TH_VEN_1	Sep 28 2021	PASS
18	A_E2_0500_TH_VEN_1	Sep 28 2021	PASS
19	A_E2_0510_TH_VEN_1	Sep 28 2021	PASS
20	A_E2_0525_TH_VEN_1	Sep 28 2021	PASS
21	A_E2_0527_TH_VEN_1	Sep 28 2021	PASS
22	A_E2_0657_TH_VEN_1	Sep 28 2021	PASS
23	A_E2_0680_TH_VEN_1	Sep 28 2021	PASS
24	A_E2_0685_TH_VEN_1	Sep 28 2021	PASS
25	A_E2_0710_TH_VEN_1	Sep 28 2021	PASS
26	A_E2_0720_TH_VEN_1	Sep 28 2021	PASS
27	A_E2_0730_TH_VEN_1	Sep 28 2021	PASS
28	A_E2_0750_TH_VEN_1	Sep 28 2021	PASS
29	A_E2_0780_TH_VEN_1	Sep 28 2021	PASS

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4.1.2.6 General Tests

No.	Test Case Name	Date	Result
01	G0_9005_TH_VEN_1	Sep 28 2021	PASS
02	G0_9010_TH_VEN_1	Sep 28 2021	PASS
03	G0_9020_TH_VEN_1	Sep 28 2021	PASS
04	G0_9030_TH_VEN_1	Sep 28 2021	PASS

4.1.2.7 XMPP Tests

No.	Test Case Name	Date	Result
01	N0_5020_TH_VEN	Sep 28 2021	PASS
02	N0_5030_TH_VEN	Sep 28 2021	PASS
03	P0_7040_TH_VEN	Sep 28 2021	PASS
04	R0_8030_TH_VEN_1	Sep 28 2021	PASS
05	E0_6030_TH_VEN_1	Sep 28 2021	PASS
06	A_E2_0525_TH_VEN_1	Sep 28 2021	PASS
07	G0_9005_TH_VEN_1	Sep 28 2021	PASS
08	G0_9010_TH_VEN_1	Sep 28 2021	PASS

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4.2 Profile 2.0a

4.2.1 VTN Pull Tests

4.2.1.1 Application Layer Test Cases

No.	Test Case Name	Date	Result
01	E3_0420_TH_VEN	Sep 28 2021	PASS
02	E3_0430_TH_VEN	Sep 28 2021	PASS
03	E3_0432_TH_VEN	Sep 28 2021	PASS
04	E3_0435_TH_VEN	Sep 28 2021	PASS
05	E3_0440_TH_VEN	Sep 28 2021	PASS
06	E3_0450_TH_VEN	Sep 28 2021	PASS
07	E3_0452_TH_VEN	Sep 28 2021	PASS
08	E3_0454_TH_VEN	Sep 28 2021	PASS
09	E3_0468_TH_VEN	Sep 28 2021	PASS
10	E3_0470_TH_VEN	Sep 28 2021	PASS
11	E3_0474_TH_VEN	Sep 28 2021	PASS
12	E3_0480_TH_VEN	Sep 28 2021	PASS
13	E3_0484_TH_VEN	Sep 28 2021	PASS
14	E3_0490_TH_VEN	Sep 28 2021	PASS
15	E3_0492_TH_VEN	Sep 28 2021	PASS
16	E3_0494_TH_VEN	Sep 28 2021	PASS
17	E3_0496_TH_VEN	Sep 28 2021	PASS
18	E3_0498_TH_VEN	Sep 28 2021	PASS
19	E3_0500_TH_VEN	Sep 28 2021	PASS
20	E3_0510_TH_VEN	Sep 28 2021	PASS
21	E3_0525_TH_VEN	Sep 28 2021	PASS
22	E3_0527_TH_VEN	Sep 28 2021	PASS
23	E3_0655_TH_VEN	Sep 28 2021	PASS
24	E3_0657_TH_VEN	Sep 28 2021	PASS
25	E3_0660_TH_VEN	Sep 28 2021	PASS
26	E3_0680_TH_VEN	Sep 28 2021	PASS
27	E3_0685_TH_VEN	Sep 28 2021	PASS
28	E3_0710_TH_VEN	Sep 28 2021	PASS
29	E3_0720_TH_VEN	Sep 28 2021	PASS
30	E3_0730_TH_VEN	Sep 28 2021	PASS
31	E3_0750_TH_VEN	Sep 28 2021	PASS
32	E3_0780_TH_VEN	Sep 28 2021	PASS

4.2.1.2 Security Test Cases

No.	Test Case Name	Date	Result
01	S3_1600_TH_VEN	Sep 28 2021	PASS
02	S3_1605_TH_VEN	Sep 28 2021	PASS

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4.2.2 VTN Push Tests

4.2.2.1 Application Layer Test Cases

No.	Test Case Name	Date	Result
01	E2_0430_TH_VEN	Sep 29 2021	PASS
02	E2_0432_TH_VEN	Sep 29 2021	PASS
03	E2_0435_TH_VEN	Sep 29 2021	PASS
04	E2_0440_TH_VEN	Sep 29 2021	PASS
05	E2_0450_TH_VEN	Sep 29 2021	PASS
06	E2_0452_TH_VEN	Sep 29 2021	PASS
07	E2_0454_TH_VEN	Sep 29 2021	PASS
08	E2_0468_TH_VEN	Sep 29 2021	PASS
09	E2_0470_TH_VEN	Sep 29 2021	PASS
10	E2_0474_TH_VEN	Sep 29 2021	PASS
11	E2_0480_TH_VEN	Sep 29 2021	PASS
12	E2_0484_TH_VEN	Sep 29 2021	PASS
13	E2_0490_TH_VEN	Sep 29 2021	PASS
14	E2_0492_TH_VEN	Sep 29 2021	PASS
15	E2_0494_TH_VEN	Sep 29 2021	PASS
16	E2_0496_TH_VEN	Sep 29 2021	PASS
17	E2_0498_TH_VEN	Sep 29 2021	PASS
18	E2_0500_TH_VEN	Sep 29 2021	PASS
19	E2_0510_TH_VEN	Sep 29 2021	PASS
20	E2_0525_TH_VEN	Sep 29 2021	PASS
21	E2_0527_TH_VEN	Sep 29 2021	PASS
22	E2_0657_TH_VEN	Sep 29 2021	PASS
23	E2_0670_TH_VEN	Sep 29 2021	PASS
24	E2_0680_TH_VEN	Sep 29 2021	PASS
25	E2_0685_TH_VEN	Sep 29 2021	PASS
26	E2_0710_TH_VEN	Sep 29 2021	PASS
27	E2_0720_TH_VEN	Sep 29 2021	PASS
28	E2_0730_TH_VEN	Sep 29 2021	PASS
29	E2_0750_TH_VEN	Sep 29 2021	PASS
30	E2_0780_TH_VEN	Sep 29 2021	PASS

4.2.2.2 Security Test Cases

No.	Test Case Name	Date	Result
01	S2_1500_TH_VEN	Sep 29 2021	PASS

4.2.3 Transport Tests

No.	Test Case Name	Date	Result
01	T9_1200	Sep 29 2021	PASS

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5 Remarks and References

Log files for the executed test cases are provided in the electronic format.

List of all executed tests with links to the log files is located in the "logfile.html" which could be opened in any web-browser.

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6 Photos

```
[openadr2.0b vtn]$ sh ./runSelect.sh config_vtn.txt -v
STARTING a VTN with the CONFIG FILE:config_vtn.txt
-v : software infomation

PRODUCT NAME   : Fujitsu Intelligent Society Solution Distributed Energy Management solution OpenADR VTN module 2.0b
PRODUCT VERSION : 1.0
OPENADR VERSION : 2.0b v1.1

[openadr2.0b vtn]$ █
```

Photo 1: FW Version

```
[openadr2.0b vtn]$ sh ./runSelect.sh config_vtn.txt
STARTING a VTN with the CONFIG FILE:config_vtn.txt
... initial processing ...

VTN is running!
```

Photo 2: System screen capture